HVC-016-1705



# MULTILAYER CERAMIC CHIP CAPACITORS

### 1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the high voltage.

The X7P product offering is ideally suited for LED driver, lighting, power, adapter and USB charge applications where effective capacitance at working voltage is critical to circuit design.

(This product is compliant with the RoHS & HF.)

#### 2. Parts Number Code

С	1210	Р	224	K	451	Т	F	F
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)

### (1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

### (2)Chip Size

Code	Length×Width unit: mm(inch)	
1210	3.20× 2.50 (.126× .098)	

### (3) Temperature Characteristics

Characteristic Range Coefficient
Characteristic Range Coefficient

(4)Capacitance unit :picc	farads(pF)
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Code	Nominal Capacitance (pF)
224	220,000.0

<sup>※.</sup> If there is a decimal point, it shall be expressed by an English capital letter R

### (5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
K	± 10.0 %	More Than 10 pF

### (6)Rated Voltage

Code	Rated Voltage (Vdc)
451	450

### (7)Tapping

Code	Туре	
T	Tape & Reel	
•		

### (8)Thickness

Code	Thickness T (mm)
F	2.00±0.30

### (9)Special Code

Code	Type	
F	Special Code	

### 3. Nominal Capacitance and Tolerance

### 3.1 Standard Combination of Nominal Capacitance and Tolerance

CI	lass	Characteristic	Tolerance	Nominal Capacitance
	II	X7P	K (± 10.0 %)	E-3, E-6 series

### 3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3		1.0				2.2			4.7			
E- 6	1.	.0	1.	.5	2	.2	3.	.3	4.	.7	6.	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

### 4. Operation Temperature Range

	Class	Characteristic	Temperature Range	Reference Temp.
ſ	I	X7P	-55℃ ~ +125℃	25℃

### 5. Storage Condition

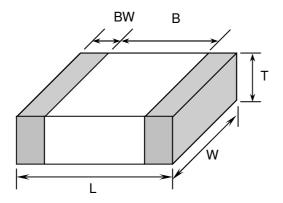
Storage Temperature : 5 to 40°C Relative Humidity: 20 to 70 % Storage Time: 12 months max.

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### 6. Dimensions

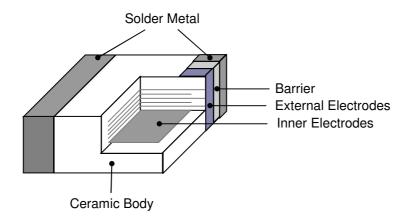
# **6.1 Configuration and Dimension:**



Unit:mm

TYPE	L	W	Т	B (min)	BW (min)
1210	3.20± 0.30	2.50± 0.20	2.00± 0.30	1.60	0.30

# 6.2 Termination Type:





# 7. Performance

No.	Item		Spe	cification	Test Condition	
1	Visua	ıl	No abnormal ex	terior appearance	Visual inspection	
2	Dimens	ion	See Page 2		Visual inspection	
3	Insulati Resistai				V≦500V, Rated Voltage Charge Time: 60sec. Is applied less than 50mA current.	
4	Capacitance	Class II	Within The Speci	fied Tolerance	Class II :  Frequency Voltage  X7P 1KHz±10% 1.0±0.2Vrms  Perform a heat temperature at 150±5°C for 30min. then place room temp. for 24±2hr.	
5	Tan $\delta$	Class	Char.	Maximum		
		П	X7P: 2.5% max.			
6	Withstan Voltag	•	No dielectric bre mechanical brea		V < 500V : 200% Rated Voltage for 1~5 sec. charge/discharge Current is less than 50mA. Voltage ramp up rate ≤ 500v/sec	
7	Temperature Capacitance Coefficient	Class II	Char. Temp. Ran X7P -55°C ~+12		Class II: (C2-C1)/C1 × 100% C1:Capacitance at standard temperature(25℃) C2: Capacitance at test temperature (T2)	
8	Adhesive S of Termin		No indication of p the terminal elect		Pull force shall be applied for 10± 1 second.  ≤ 06035N( = 0.5 Kg·f)  > 060310N( = 1.0 Kg·f)  N·f	
9		ance	Capacitance Cha Char.		Bending shall be applied to the 1.0 mm with  1.0 mm/sec.  R230  Bending  Limit  C Meter  45±1mm  45±1mm	



# MULTILAYER CERAMIC CHIP CAPACITORS

No.	Item		Specifi	ication	Test Condition	
10	Solderability		More than 90% of the is to be soldered ne does not come out of	wly, so metal part	Solder Temperature: 245±5°C  Dip Time: 5 ± 0.5 sec.  Immersing Speed: 25±10% mm/s  Solder: Lead Free Solder  Flux: Rosin  Preheat: At 80~120 °C for 10~30sec.	
11	Resistance To Soldering Heat	Appearance Capacitance  Tan δ Class II Insulation Resistance Withstand Voltage	Characteristic Class X7P II To satisfy the specif To satisfy the specif	Cap. Change Within ± 10% ied initial value ied initial value	Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat treatment at 150 +0/-10 ℃ before initial measure.  Preheat: At 150± 10 ℃ For 60~120sec.  Dip: Solder Temperature of 260± 5 ℃  Dip Time: 10± 1sec.  Immersing Speed: 25±10% mm/s  Flux: Rosin  Measure at room temperature after cooling for Class II: 48±4 Hours	
12	Tempera ture Cycle	Appear- ance Capacit- ance Tan δ Class II Insulation Resistance	Characteristic Class X7P II To satisfy the specif To satisfy the specif	Cap. Change Within ± 7.5% ied initial value	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure.  Capacitor shall be subjected to five cycles of the temperature cycle as following:  Step Temp.(°C) Time(min)  1 Min Rated Temp. +0/-3 30  2 25 3  3 Max Rated Temp. +3/-0 30  4 25 3  Measure at room temperature after cooling for Class II :48 ± 4 Hrs  Solder the capacitor on P.C. board shown in Fig 2. before testing.	
13	Humidity	Appear- ance Capacit- ance  Tan δ Class II Insulation Resistance	No mechanical dam  Characteristic Class X7P II  Char. X7P: 5.0% max. 50/C Ω min.	Cap. Change Within ± 15%  Maximum	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150+0/-10 °C before initial measure.  Temperature: 40± 2°C Relative Humidity: 90 ~ 95%RH Test Time: 500 +12/-0Hr  Measure at room temperature after cooling for Class II: 48 ± 4Hrs  Solder the capacitor on P.C. board shown in Fig 2. before testing.	

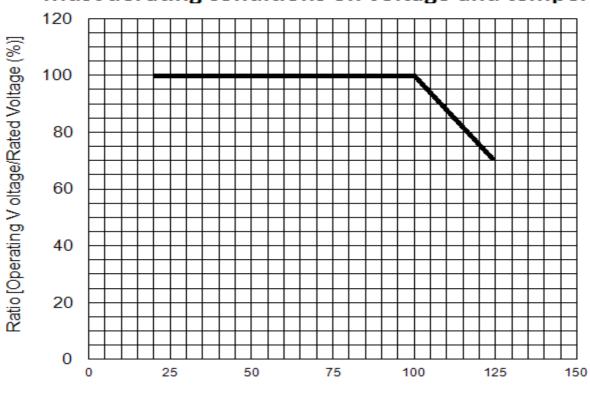
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No.	Ite	m		Specifi	cation	Test Condition
14	_ High	Appear-	No me	chanical dar	mage shall occur	Class II capacitors applied DC voltage (following
	Temperature	ance				table) is applied for one hour at maximum
	Load	Capacit-	Char	acteristic	Cap. Change	operation temperature $\pm 3^{\circ}$ C then shall be set for
	(Life Test)	ance	Class	X7P	Within ± 15%	48±4 hours at room temperature and the initial
			П			measurement shall be conducted.
		Tan $\delta$	Cha	ar.	maximum	Applied Voltage: 100%Rated Voltage
		Class II	X7P :	5.0% max.		
		Insulation	<b>50/C</b> Ω	min.		
		Resistance				Test Time: 1000 +12/-0Hr
						Current Applied: 50 mA Max.
						Measure at room temperature after cooling for
						Class II: 48 ± 4 Hours
15	Vibration	Appear-	No me	chanical dar	nage shall occur	Solder the capacitor on P.C. Board shown in
		ance				Fig 2. before testing.
		Capacit-	Char	acteristic	Cap. Change	
		ance	Class	X7P	Within ± 7.5%	Vibrate the capacitor with amplitude of 1.5mm
			П			P-P changing the frequencies from 10Hz to
		Tan $\delta$	To satis	sfy the spec	ified initial value	55Hz and back to 10Hz in about 1 min.
		Class ∏				
		Insulation	To satis	sfy the spec	ified initial value	Repeat this for 2 hours each in 3perpendicular
		Resistance		•		directions.

When operating at temperature range from  $100^\circ\mathbb{C}$  to  $125^\circ\mathbb{C}$ , the operation shall be carried out at a derating voltage or less as shown below

# Must derating conditions on voltage and temperature



Temperature at Product (°C)

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Fig.1
P.C. Board for Bending Strength Test

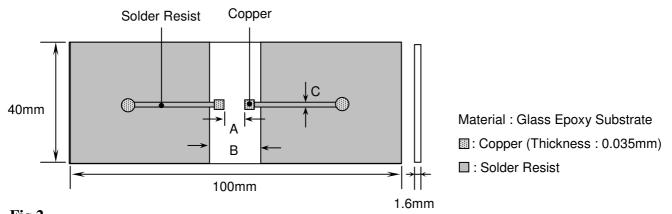
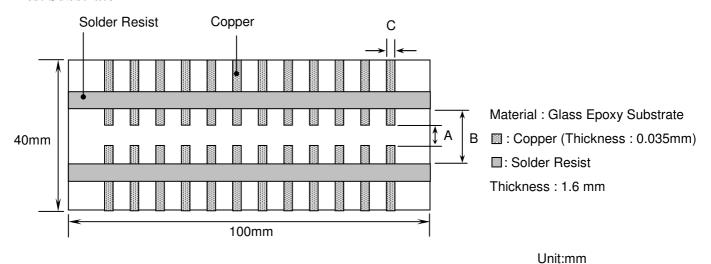


Fig.2
Test Substrate



Type	Α	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
1825	3.5	7.0	6.9
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6
2225	4.5	8.0	7.0

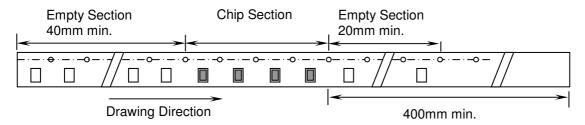


### 8. Packing

### 8.1 Bulk Packing

According to customer request.

### 8.2 Chip Capacitors Tape Packing



### 8.3 Material And Quantity

Tape	0201	0402	0603/	0805
Material	T≦0.33mm	T≦0.55mm	T≦1.00mm	T>1.00mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	1210/	1808	
Material	T≦1.00mm	1.00mm < T ≤ 1.25mm	T>1.25mm	T≦1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel	3000 pcs/Reel	2000 pcs/Reel

Tape	1812/1825	/2211/2220	22	25	2208
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	1000 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

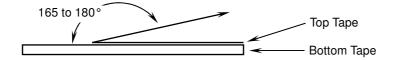
NA: Not Available

### 8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$ 

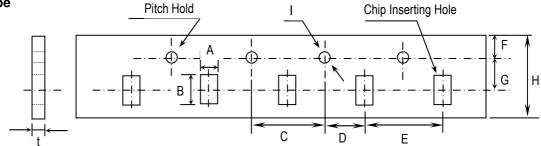
8.4.2 Measure Method



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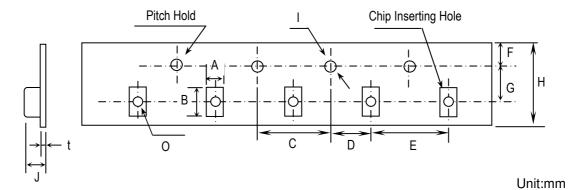


### Unit:mm

TYPE	Α	В	С	D	Е
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

# 8.6 Plastic Tape



Type	Α	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				

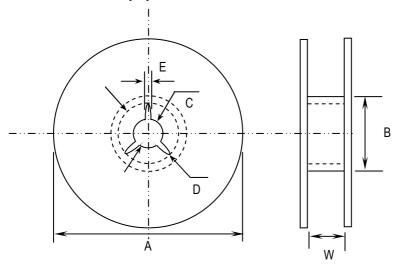


# MULTILAYER CERAMIC CHIP CAPACITORS

Туре	G	Н		J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

# 8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	Α	В	С	D	Е	W
0201	$\varphi$ 382 max	arphi 50 min	$\varphi$ 13± 0.5	$\varphi$ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



### **Precautionary Notes:**

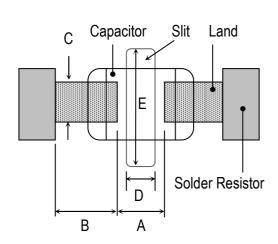
#### 1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

#### 2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

2.1 Size and recommend land dimensions for reflow soldering .

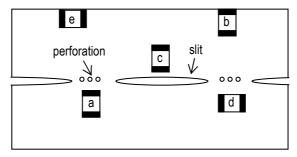


EIA Codo	Chip (mm)		Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		-
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		-
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		-
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.

Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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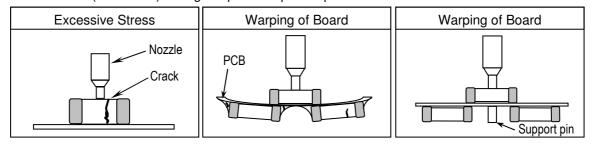


### 2.3 Layout Recommendation

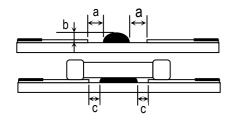
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder  Adhesive PCB Solder Land	Chassis  Excessive Solder  a	Solder Land
Recommendation	Chip Solder Resist  Adhesive PCB Solder Land	Solder Resist $\alpha > \beta$	

### 3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



### 3.2 Amount of Adhesive



Example: 0805 & 1206 a 0.2mm min.

а	0.2mm min.
b	70 ~ 100 μm
С	Do not touch the solder land

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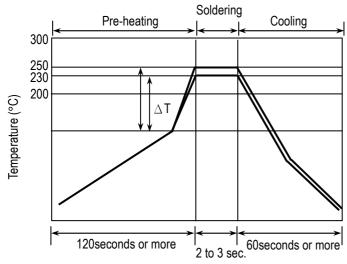


#### 4. Soldering

#### 4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to  $250\,^{\circ}$ C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

### **Recommend flow soldering temperature Profile**



Soldering Method	Change in Temp.( $^{\circ}$ C)
1206 and Under	$\Delta T \le 100 \sim 130 \text{ max}.$

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
  - a. Flux flows to easily
  - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
  - a. Flux deteriorates even when oxide film is removed
  - b. Causes warping of circuit board
  - c. Loss of reliability in chip and other components

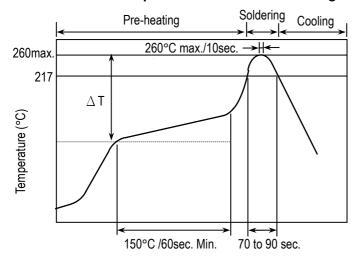
### Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference ( $\Delta T$ ) between the solvent and the chips must be less than 100 °C.

### 4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed  $3^{\circ}$ C/Sec.

#### Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



### ※ The cycles of soldering : Twice (max.)

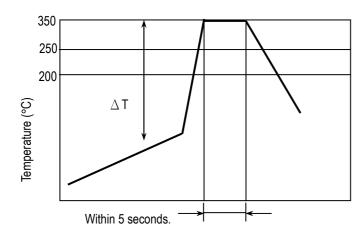
Soldering Method	Change in Temp.( $^{\circ}$ C)
1206 and Under	∆ T ≦ 190 °C
1210 and Over	∆ T ≦ 130 °C

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#### 4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.( °C)
1206 and Under	$\Delta$ T $\leq$ 150 $^{\circ}$ C
1210 and Over	$\Delta$ T $\leq$ 130 $^{\circ}$ C

#### How to Solder Repair by Solder Iron

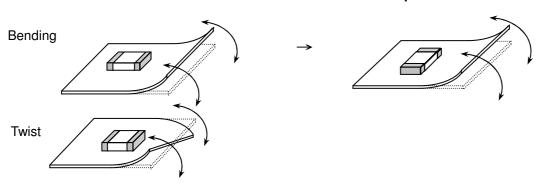
- 1) Selection of the soldering iron tip
  - The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.
- 2) recommended solder iron condition
  - a.) Preheating Condition: Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
  - b.) Soldering iron power shall not exceed 30 W.
  - c.) Soldering iron tip diameter shall not exceed 3mm.
  - d.) Temperature of iron tip shall not exceed 350 ℃., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
  - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
  - g.) After soldering operation, let the products cool down gradually in the room temperature.

### 5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

# Higher potential of crack

#### Lower potential of crack



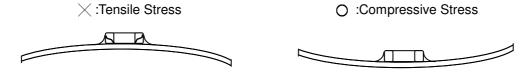
5.2 There is a potential of crack if board is warped due to excessive load by check pin



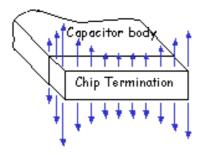
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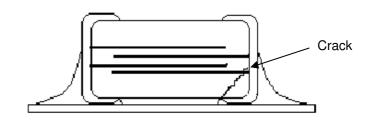


- 5.3 Mechanical stress due to warping and torsion.
  - (a) Crack occurrence ratio will be increased by manual separation.
  - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



# Capacitor Stress Analysis



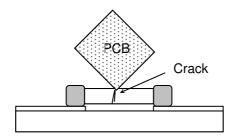


### 6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



### 7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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